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| 1. Record Nr. | UNINA9910808257703321 |
| Autore | Tackett Nicolas |
| Titolo | The Destruction of the Medieval Chinese Aristocracy // Nicolas Tackett |
| Pubbl/distr/stampa | Boston : , : Harvard University Asia Center, , 2014 Leiden; ; Boston : , : BRILL, , 2014 |
| ISBN | 1-68417-077-X |
| Edizione | [1st ed.] |
| Descrizione fisica | 1 online resource (xiv, 281 pages :) : illustrations, maps ; |
| Collana | Harvard University Studies in East Asian Law ; ; 93 |
| Disciplina | 951/.01708621 |
| Soggetti | Aristocracy (Social class) Elite (Social sciences) Manners and customs Power (Social sciences) China History Tang dynasty, 618-907 China History Tang dynasty, 618-907 Sources China Social life and customs 221 B.C.-960 A.D China Social conditions 221 B.C.-960 A.D |
| Lingua di pubblicazione | Inglese |
| Formato | Materiale a stampa |
| Livello bibliografico | Monografia |
| Nota di bibliografia | Includes bibliographical references and index. |
| Nota di contenuto | Map of Tang China -- Conventions -- Introduction -- The transformation of medieval elites -- Tomb epitaphs as a historical source -- Chapter One. The bureaucratic aristocracy of medieval China -- Chapter Two. The geography of power -- Chapter Three. Capital elite marriage networks -- Chapter Four. The late Tang provinces -- Chapter Five. Huang Chao and the destruction of the medieval aristocracy -- Appendix A: Guide to the accompanying database -- Appendix B: Estimating the total size of the late Tang capital elite -- Appendix C: Sources of ninth-century excavated epitaphs. |
| Sommario/riassunto | "Tackett resolves the enigma of the complete disappearance by the tenth century of the medieval Chinese aristocracy, analyzing a dazzling array of sources to demonstrate that the great Tang aristocratic families were far more successful than previously believed in adapting to the many transformations of the seventh and eighth centuries"-- |

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| 2. Record Nr. | UNINA9910760270703321 |
| Autore | Eremenko Volodymyr |
| Titolo | Advanced Information-Measuring Technologies and Systems I // edited by Volodymyr Eremenko, Artur Zaporozhets |
| Pubbl/distr/stampa | Cham : , : Springer Nature Switzerland : , : Imprint : Springer, , 2024 |
| ISBN | 9783031407185 3031407180 |
| Edizione | [1st ed. 2024.] |
| Descrizione fisica | 1 online resource (282 pages) |
| Collana | Studies in Systems, Decision and Control, , 2198-4190 ; ; 439 |
| Altri autori (Persone) | ZaporozhetsArtur |
| Disciplina | 620 |
| Soggetti | Engineering mathematics Engineering - Data processing Mechanical engineering Mathematical and Computational Engineering Applications Mechanical Engineering Data Engineering |
| Lingua di pubblicazione | Inglese |
| Formato | Materiale a stampa |
| Livello bibliografico | Monografia |
| Nota di contenuto | Preface -- Contents -- Metrological Support of Measurement Channels with Bridge Circuits -- Application of Exponential Splines in the Measurement and Control of Electric Circuit Parameters -- Improving of Methods of Impedance Parameters Units Reproduction and Measurement Accuracy Increasing for Ensuring Metrological Traceability -- Implementation of Information and Measurement Systems at the Base Specialized Internet Protocols -- Model of Information Signals Formation in the Diagnostics of Composite Products -- Theory and Practice of Ensuring the Validity in Testing Laboratories -- Methodology for Controlling Greenhouse Microclimate Parameters and Yield Forecast Using Neural Network Technologies. |
| Sommario/riassunto | The book presents the main scientific directions and issues of research conducted in the Department of Information and Measurement Technologies at the National Technical University of Ukraine "Ihor Sikorskyi Kyiv Polytechnic Institute". The presented results cover almost all scientific directions related to information and measurement technologies—metrological support of measurement channels of |

information and measurement systems, methods of reproducing units of electric circuit parameters, development of specialized information and measurement systems, mathematical methods of processing measurement information, models of formation of information signals and fields, statistical diagnostic methods, information support of testing, and calibration laboratories.
